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| Notice of References Cited | Application/Control No. 10/518,915 | Applicant(s)/Patent Under Reexamination YANO ET AL. | |
| | Examiner Amy L. Clark | Art Unit 1655 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| * | A | US-6,372,234 B1 | 04-2002 | Deckers et al. | 424/401 |
| * | B | US-6,077,520 | 06-2000 | Tominaga, Naoki | 424/401 |
| * | C | US-6,042,841 | 03-2000 | Alaluf et al. | 424/401 |
| * | D | US-5,747,049 | 05-1998 | Tominaga, Naoki | 424/401 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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